



Development of thin films for superconducting RF cavities in ASTeC

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on behalf of collaboration team 

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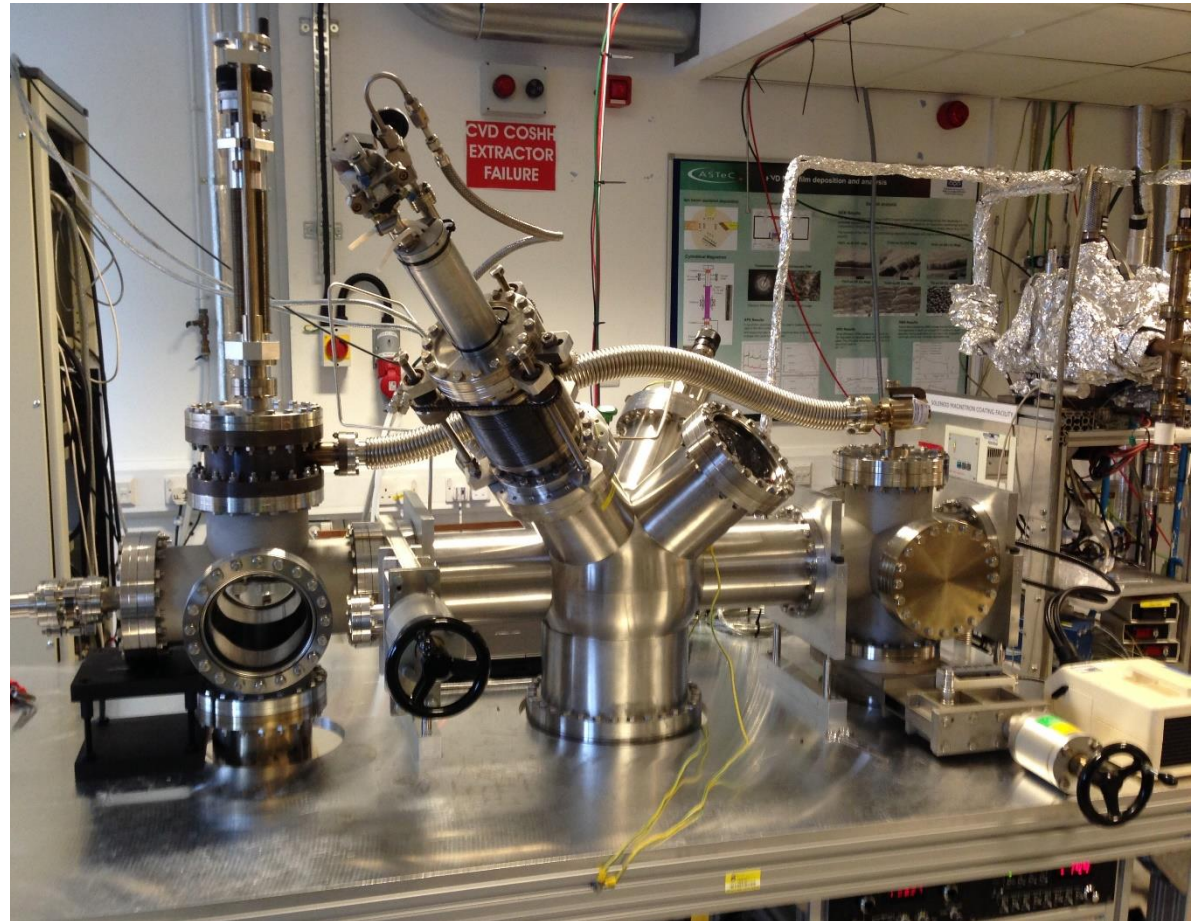


Motivation

- The aim is to develop the PVD and CVD coating technologies of superconducting materials for RF cavities and apply it on the RF cavities
- Objectives:
 - a systematic study of
 - Deposition parameters
 - Film morphology, structure, chemistry
 - AC and DC superconductivity characteristics such as T_c , B_c , RRR, etc.
 - RF evaluation of samples
 - Cavity deposition and test

UHV PVD facility

- Bakeable
- Load-lock chamber
- ≤ 100 mm diam.
- Three planar concentric targets with the variable distance to the substrate: 10-15 cm
- Substrate rotation
- Ion beam assist,
- $20 \leq T_s \leq 950$ °C
- Differential RGA pumping to analyse the sputter gas.

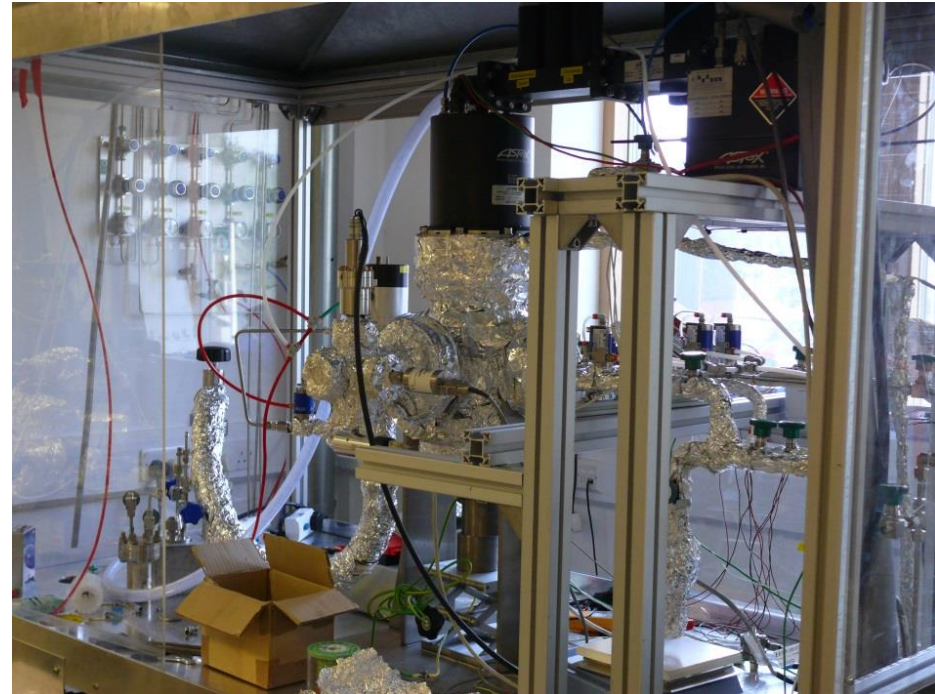


- HiPIMS and Pulsed DC,

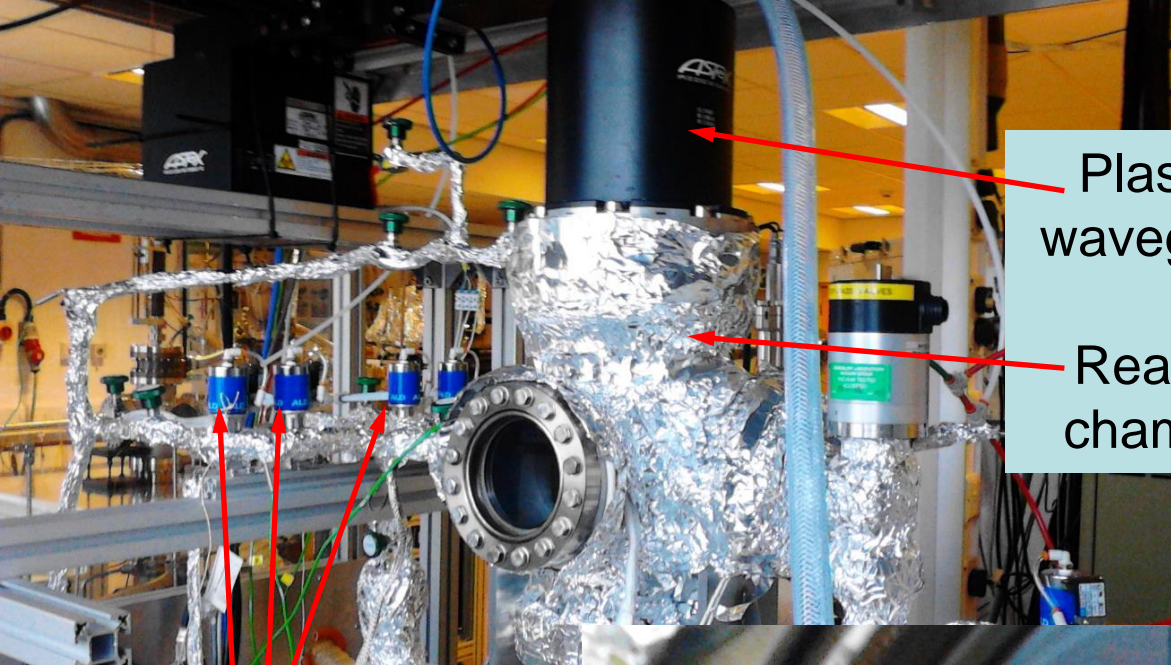
FCC, USA

PECVD/ALD deposition

- Base pressure:
 - 1.5×10^{-5} mbar at 120 °C
- Gas flows:
 - Argon, Max 5 l/min, 200 sccm MFC
 - Hydrogen, Max 1 l/min, 100 sccm MFC
- Heater tested up to 700 °C (could go 950 °C)



ALD rig



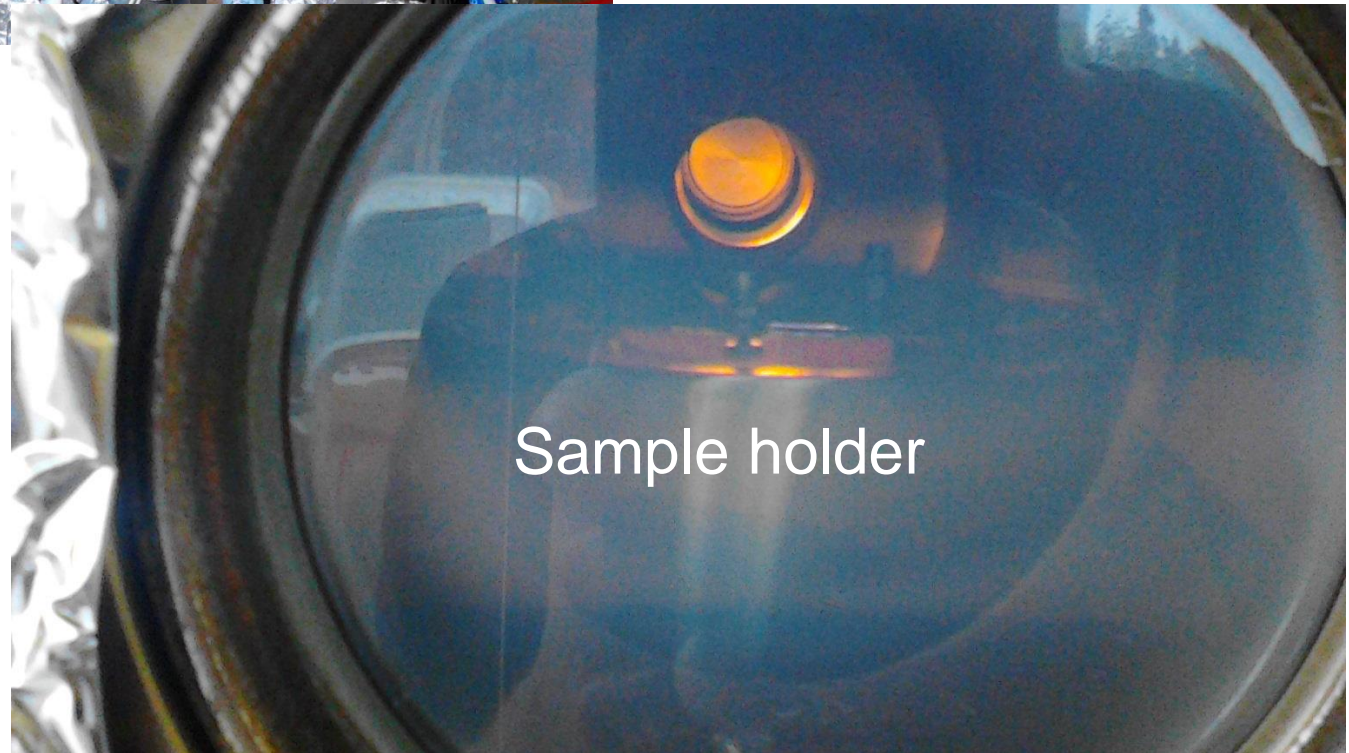
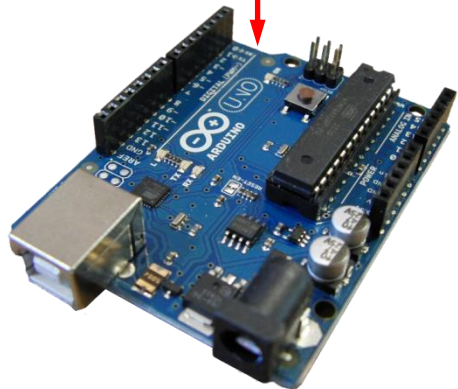
Plasma waveguide

Reactor chamber

SAES gas purifiers

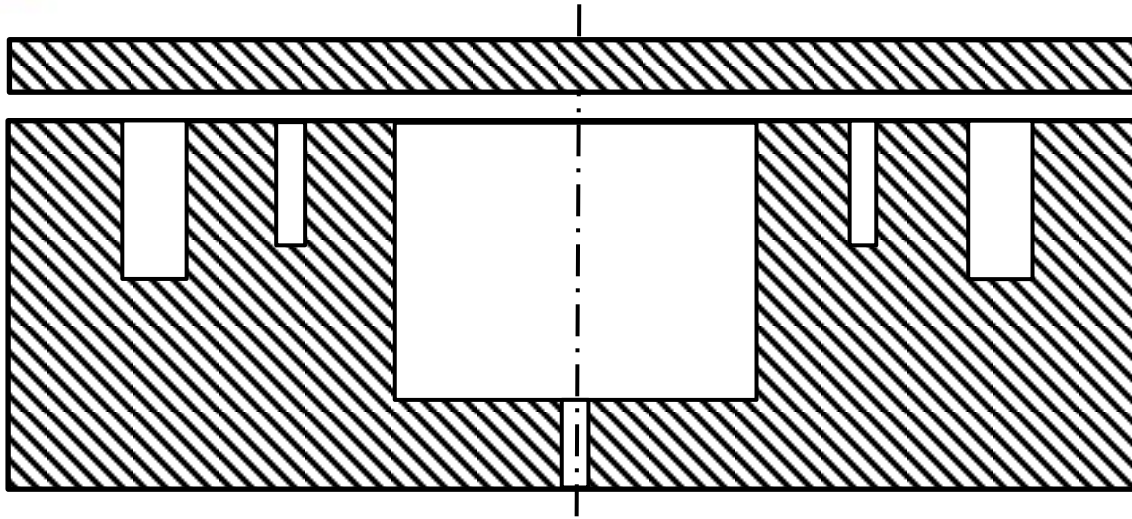


ALD valves:
tested with
Arduino control,
switching <1 ms



Sample holder

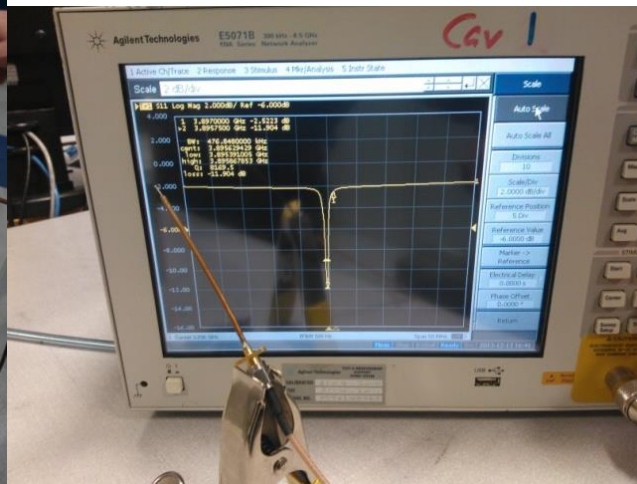
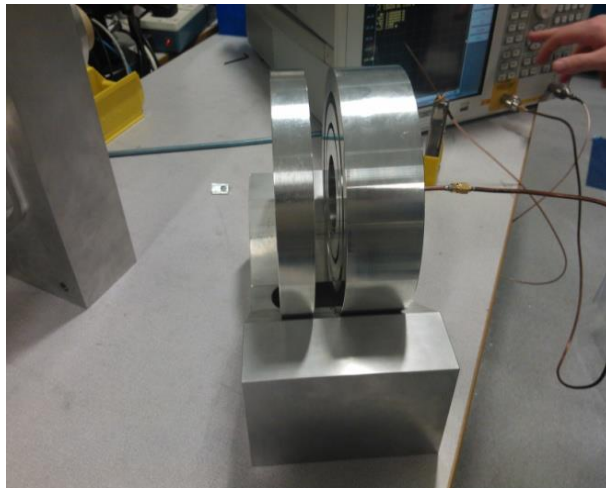
Pill BOX Cavity: Aluminium mock up RF cavity test



- Mock up 3.9 GHz pill box cavity has been fabricated to validate the simulation results obtained with Microwave Studio.
- An order for a niobium 7.8 GHz cavity is in place.

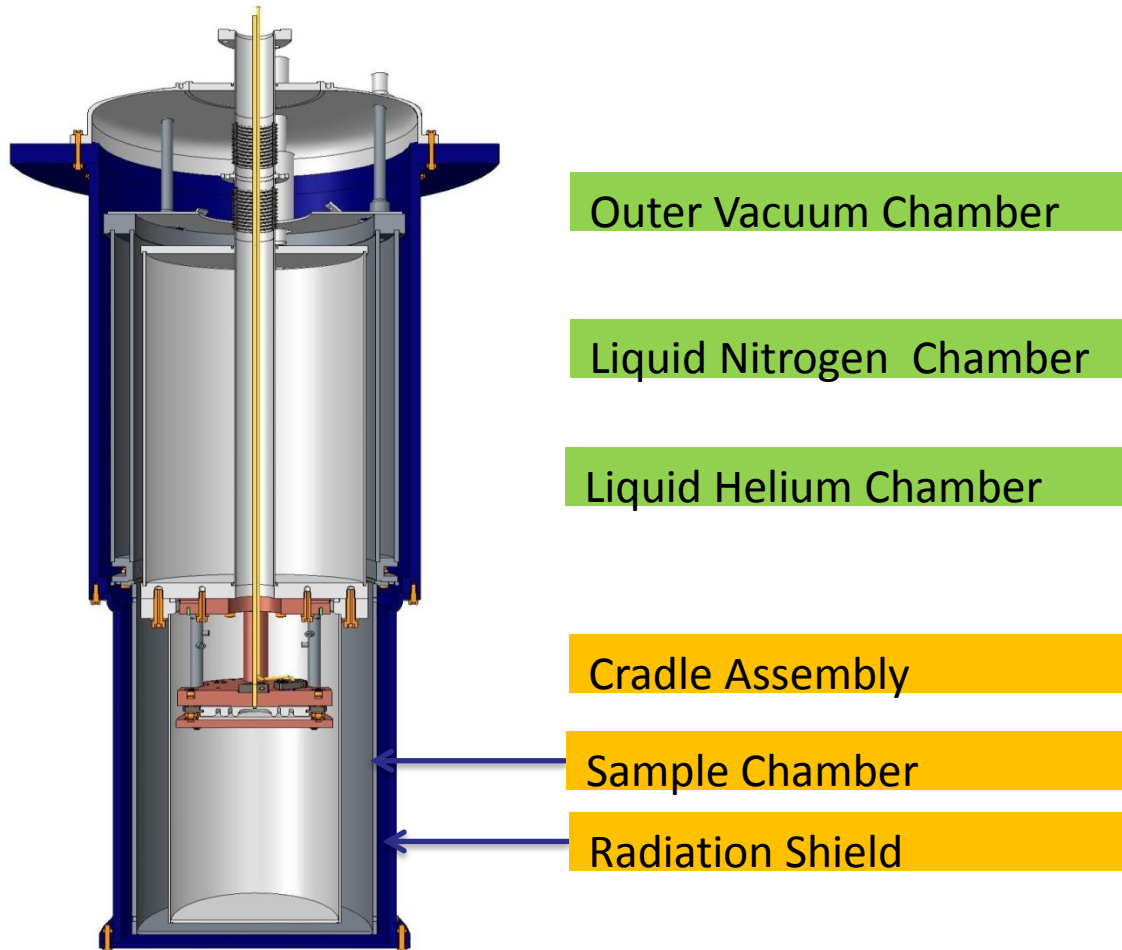
Samples:

- a 100-mm diam. Nb disk
- a 100-mm diam. copper disk with thin films of Nb deposited on the surface.



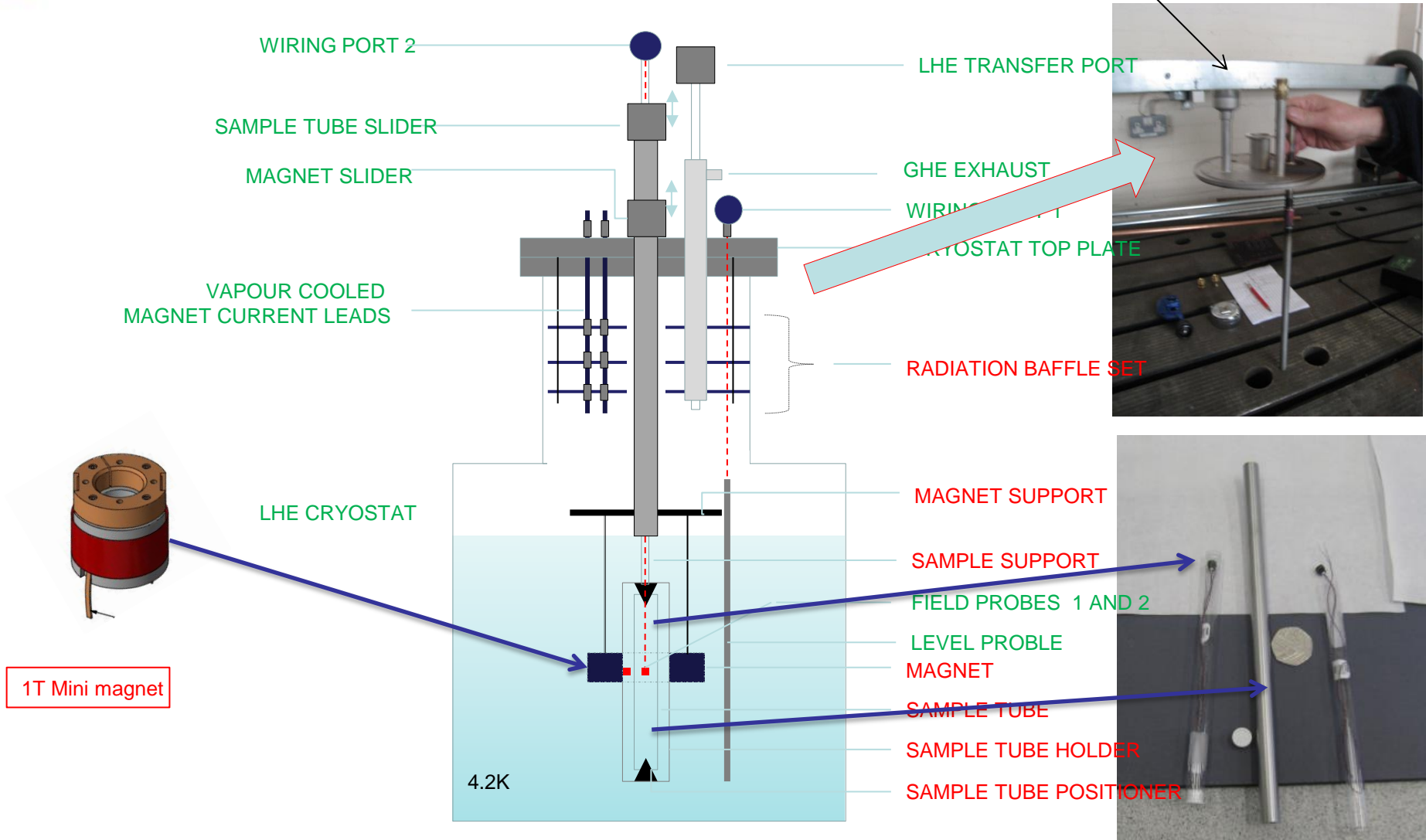


LHe CAVITY CRYOSTAT



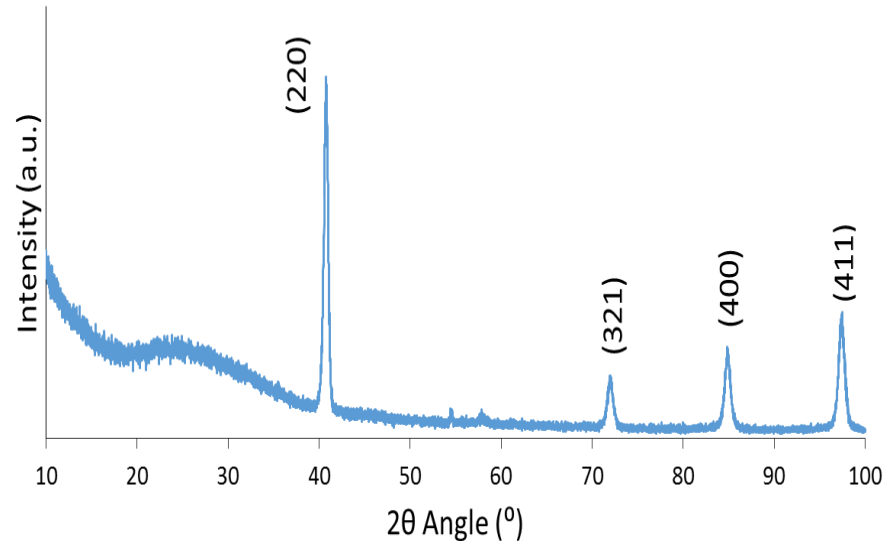


Magnetic field penetration measurement experiment suggested by A.Gurevich



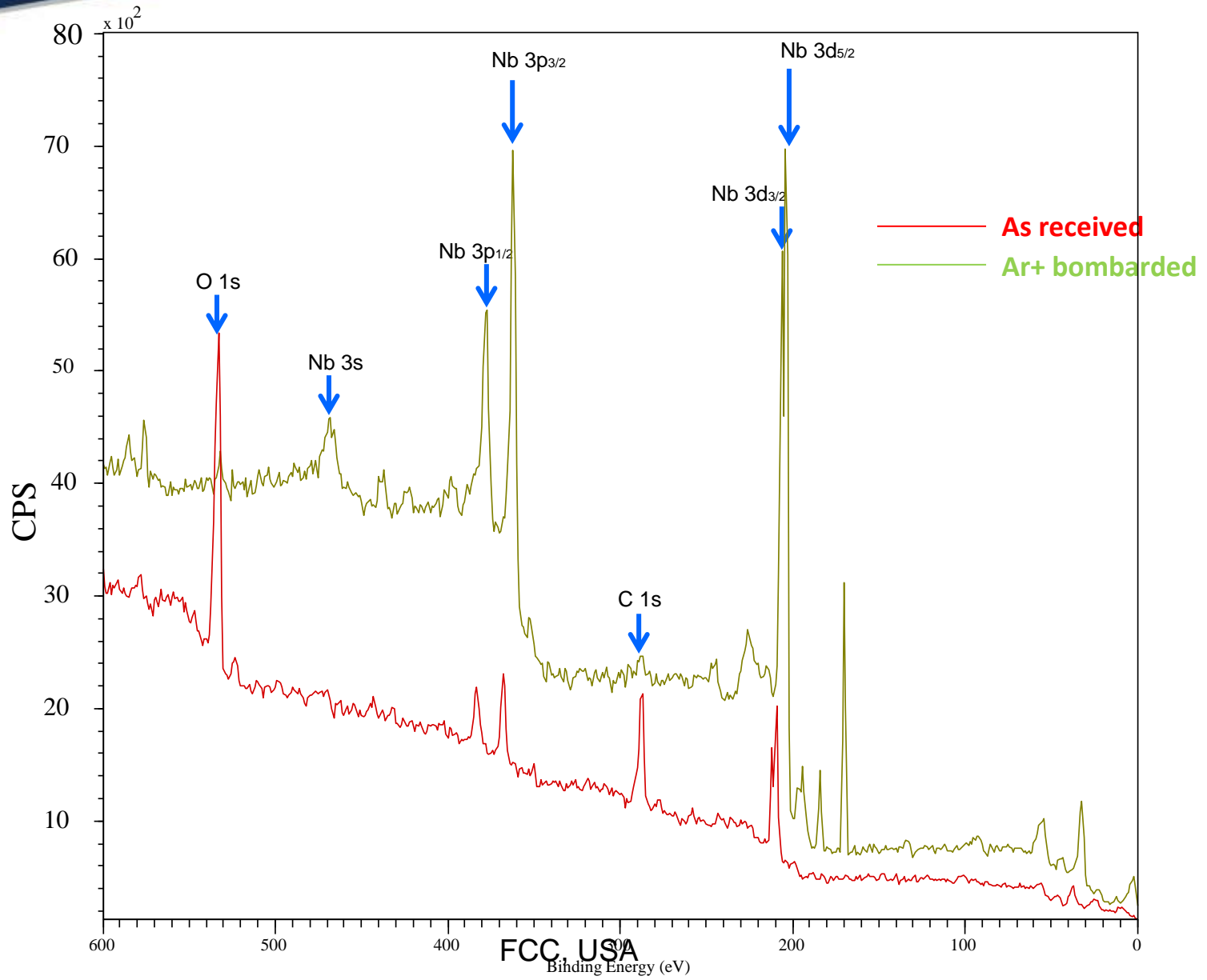
Film Morphology: XRD

- Nb grain sizes within our films:
18 -73 nm
- This is similar in size to the grains produced in other studies.
- The films are polycrystalline and highly textured with the preferred direction of growth depending on the substrate orientation and deposition condition
- RRR values shows no dependence to a preferred orientation



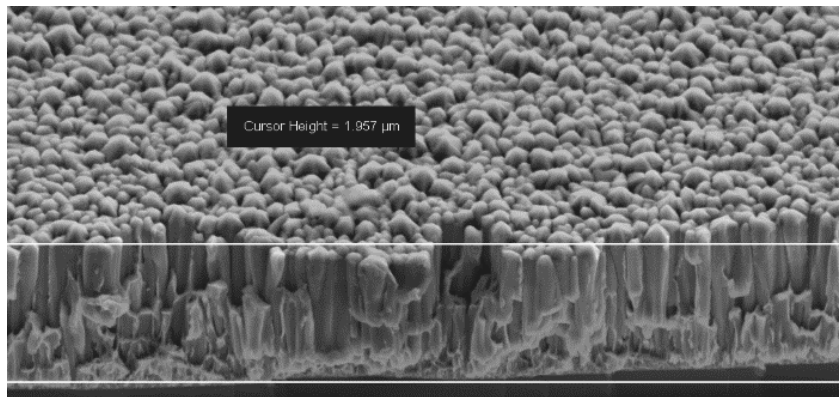


XPS analysis

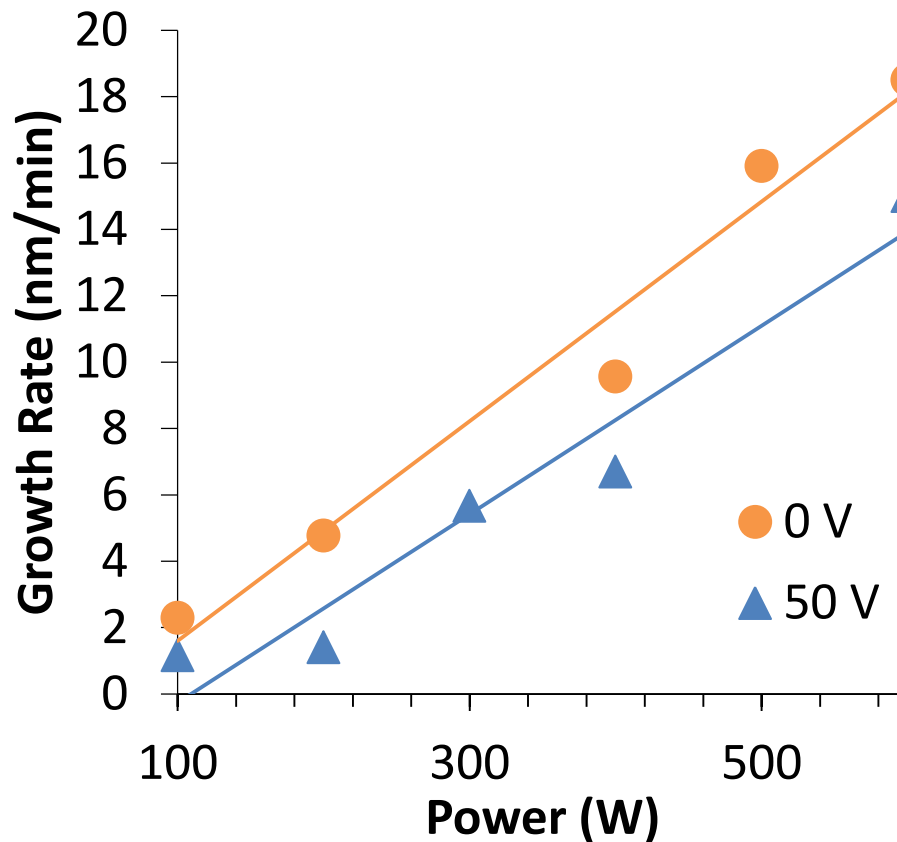
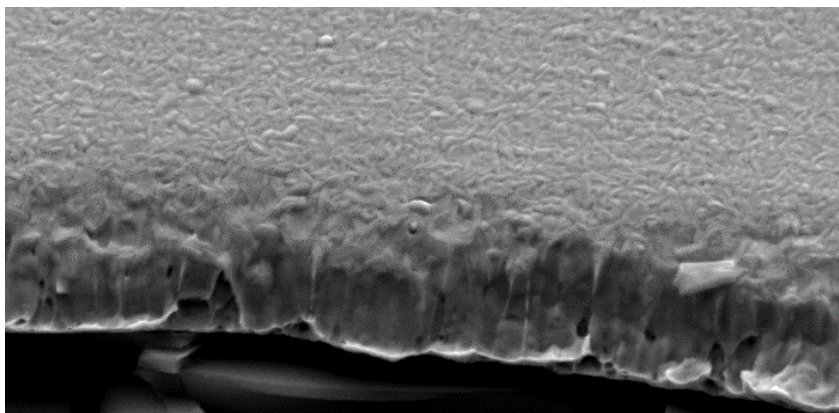


Film Morphology: SEM

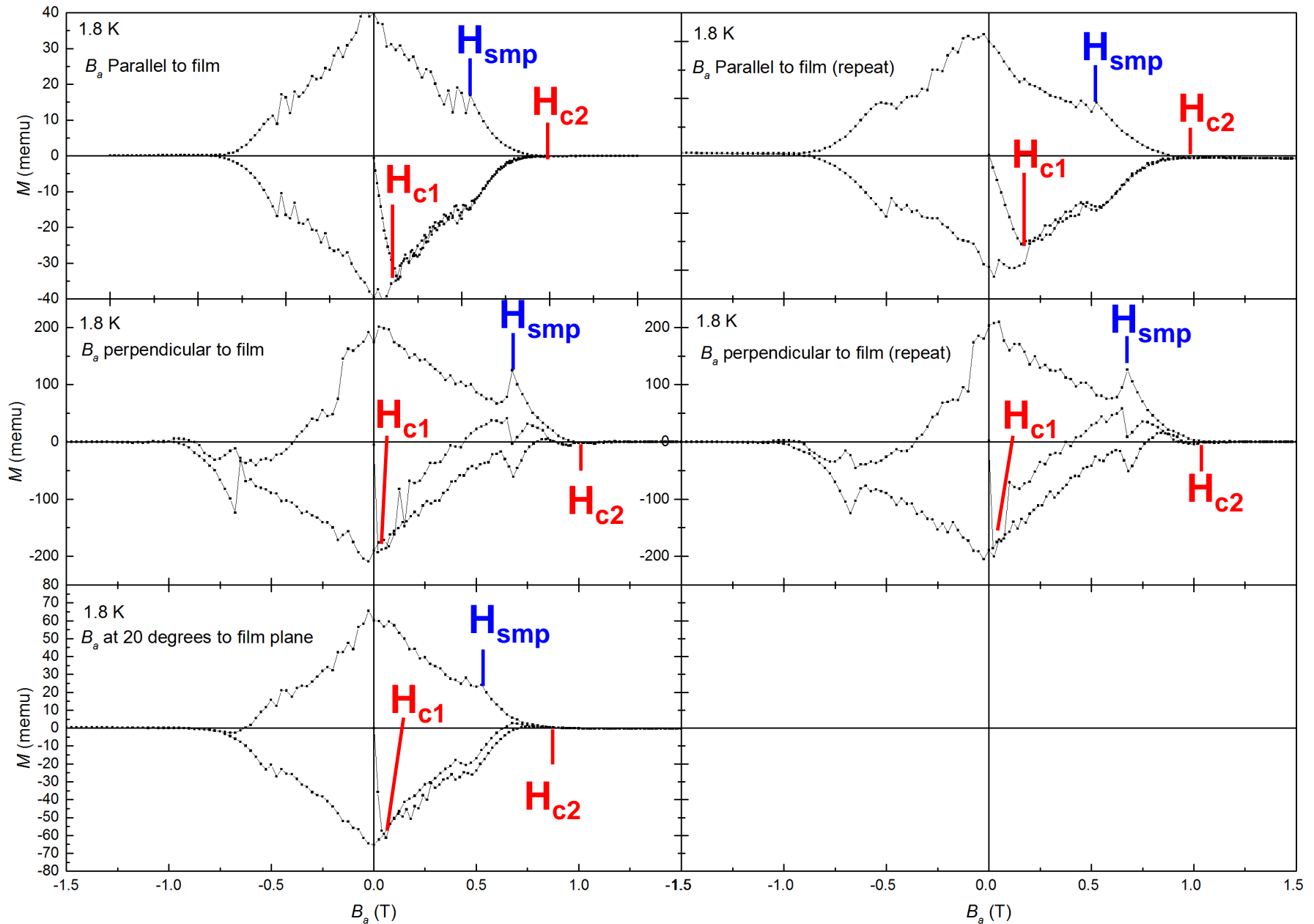
samples deposited without a bias



samples deposited
with a 50-V bias



Superconductivity evaluation: DC SQUID

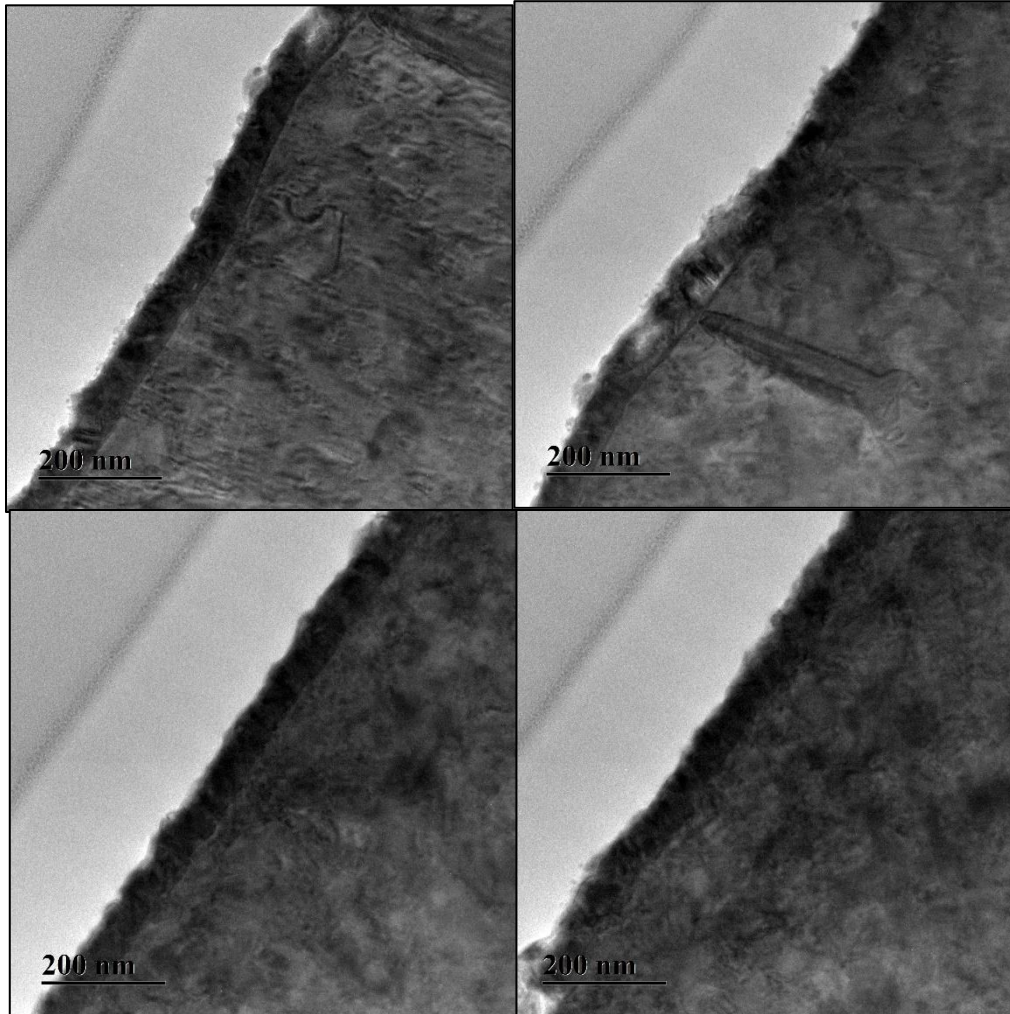




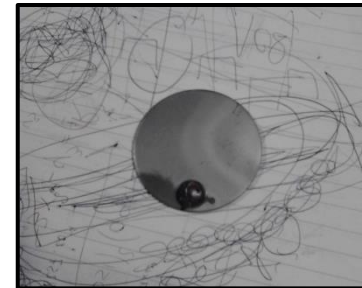
PVD SUMMARY of RESULTS

- Largest grains of 73 nm deposited by HiPIMS on MgO
- Increasing grain size expected to increase H_{c1}
- H_{c1} has ranged from 0.1 to 0.18 T on Cu and Si substrate
- H_{c2} for films deposited by HiPIMS has been approx. 0.4 T and lower than for DC sputtered films
- Low H_{c2} expected of large grain films and is approaching values expected of bulk Nb (approx. 0.27 T)
- More stable pinning for films deposited onto Cu substrate when compared to Si substrate
- Films deposited onto Si show large flux jumps
- RRR approximately doubles for films deposited onto Cu when compared to Si however no correlation between RRR and H_{c2}
- Films with higher RRR showed fewer flux jumps

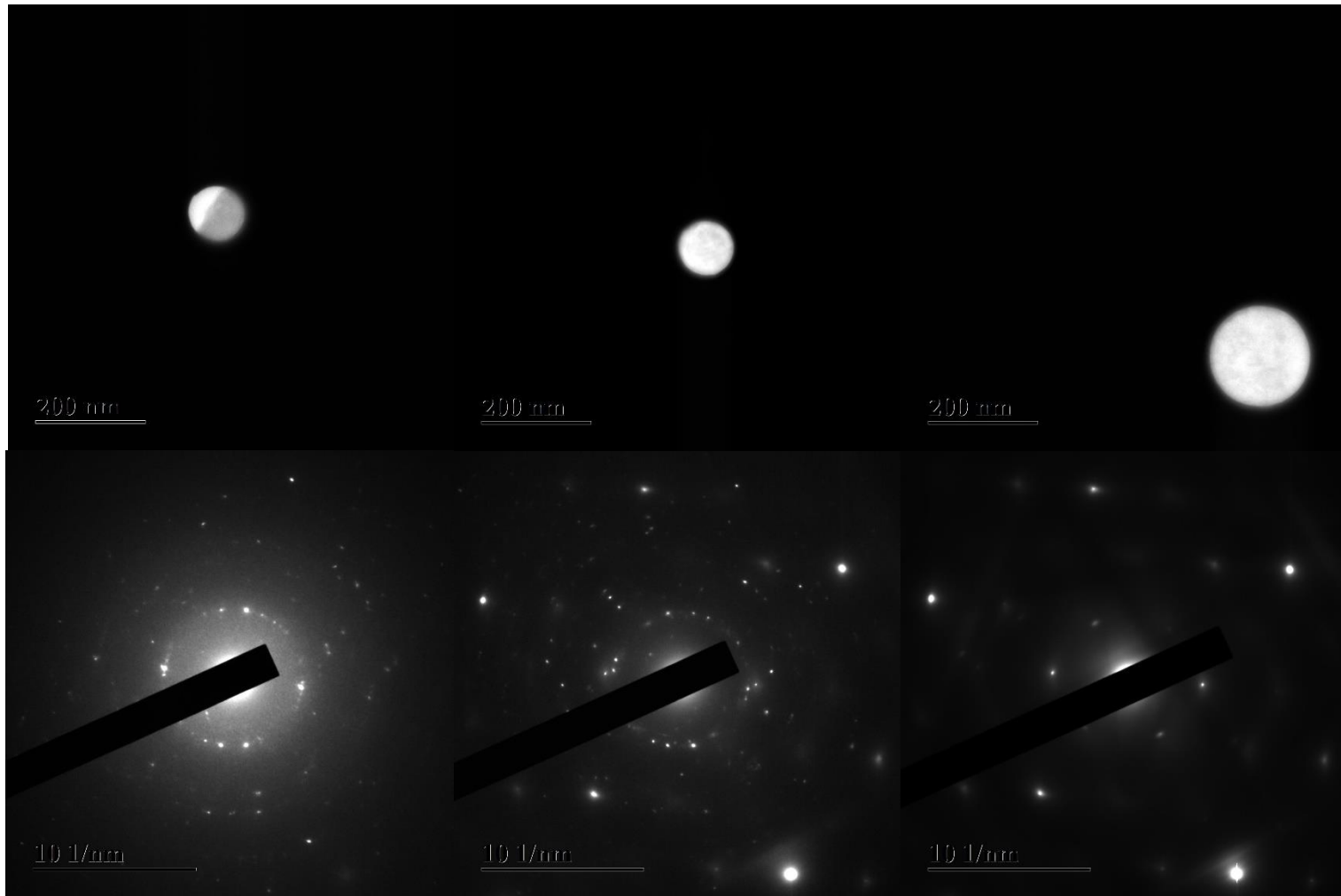
CVD deposition of Nb on Cu



- Nb(v) Cl
- Deposited at 650°C
- $T_c = 8K$
- RRR = 31



CVD Nb – Electron diffraction





Conclusions

- Quality of the film (morphology, RRR, H_{c2}) depends on
 - deposition parameters such as
 - Substrate temperature,
 - Ion/atom arrival ratio,
 - Substrate bias,
 - Plasma generation at the target
 - DC pulsed or DC
 - HiPIMS
 - Substrate crystallography
 - For CVD/ALD precursor and deposition Temperature



Conclusions (2)

- Sample evaluation
 - RF pill-box cavity is the best, however
 - High Cost of manufacturing and cost of LHe,
 - Time consuming
 - AC and DC susceptibility:
 - Not direct for RF (H_{c1} and H_{c2}) and a cost of LHe
 - Quicker
 - T_C and RRR is an initial of evaluation
 - $RRR > 10^{-73}$, but does not correlate with RF
 - Quick, cheap
 - Surface analysis to determine:
 - Dense or columnar
 - Grain size,
 - Composition and impurity
 - Defects density



Future plans

- HiPIMS sample deposition for
 - Nb, NbN, NbCN, Nb₃Ge MgB₂
- Plasma ALD deposition
 - Nb, NbN, NbCN, MgB₂
- Continuing RRR measurements
- AC and DC magnetisation measurements
- Magnetic field penetration SCI multilayer layer
- RF pill-box test facility
 - Testing with a bulk Nb disk (April 2015)
 - Sample measurements (May 2015)
- 3D coating (2016)

The UK's SRF collaboration team



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